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Barry Lai
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Introduction

It has been a pleasure to organize the SPIE X-ray Nanoimaging Conference. It started from a simple office visit by a longtime colleague, Ali Khounsary, who had organized numerous SPIE x-ray conferences. With Ali's encouragement and advice, I started to contact potential members of the program committee. Surprisingly everyone accepted and agreed to serve, and an international program committee was quickly established. However the most remarkable occurrence had to be the enthusiastic response from the x-ray nanoimaging community: 48 original and exciting abstracts were submitted within a short time. It demonstrated the breadth and depth of the x-ray nanoimaging community in general, which had seen substantial growth recently due to construction of new and upgrade of existing synchrotron facilities worldwide.

The conference was organized into two days of oral presentations, with a lively evening poster session in between. Topics included scanning probes, full-field microscopes, in-situ studies, nanofocusing optics, beam characterization, fast instrumentation, novel methods, and lab-based instruments. Overall the presentations were exciting, the audiences were engaging, and it was particularly gratifying to see new researchers participating at the conference. Special thanks to the program committee members for their volunteer but hard work, the SPIE staff for their professional support, session chairs for managing the thoughtful discussions, authors and presenters for sharing the latest developments, and all the active participants, who together made this a very rewarding experience.

Barry Lai